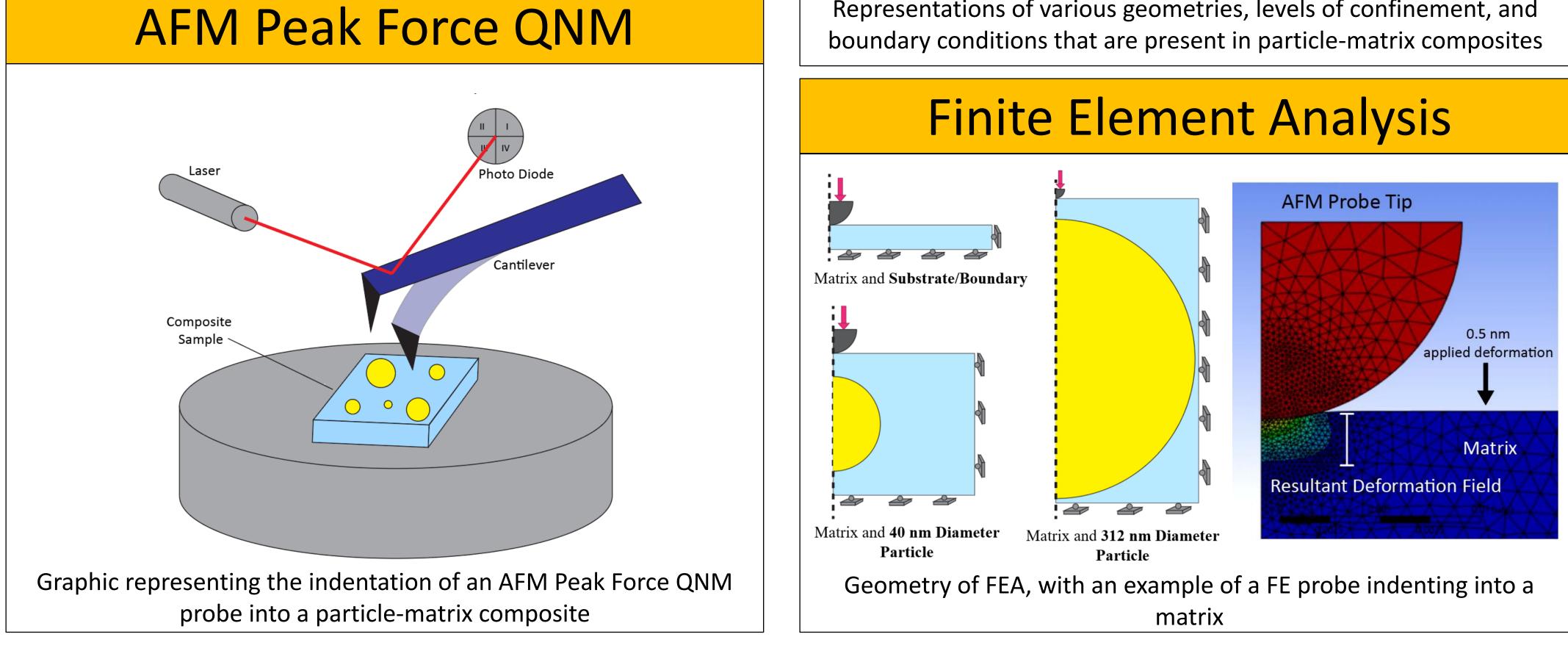
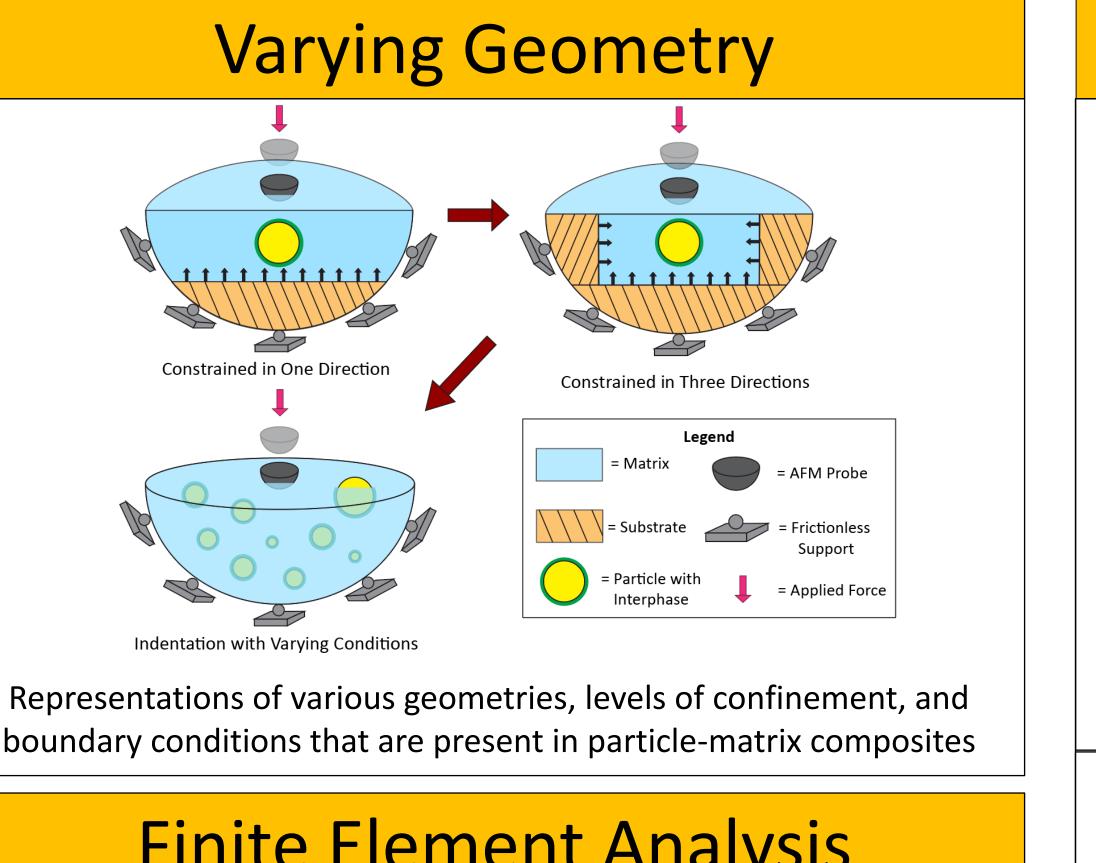
Finite Element Analysis of Atomic Force Microscopy (AFM) Measurement of Inhomogeneous Nodules **Suspended in a Membrane**

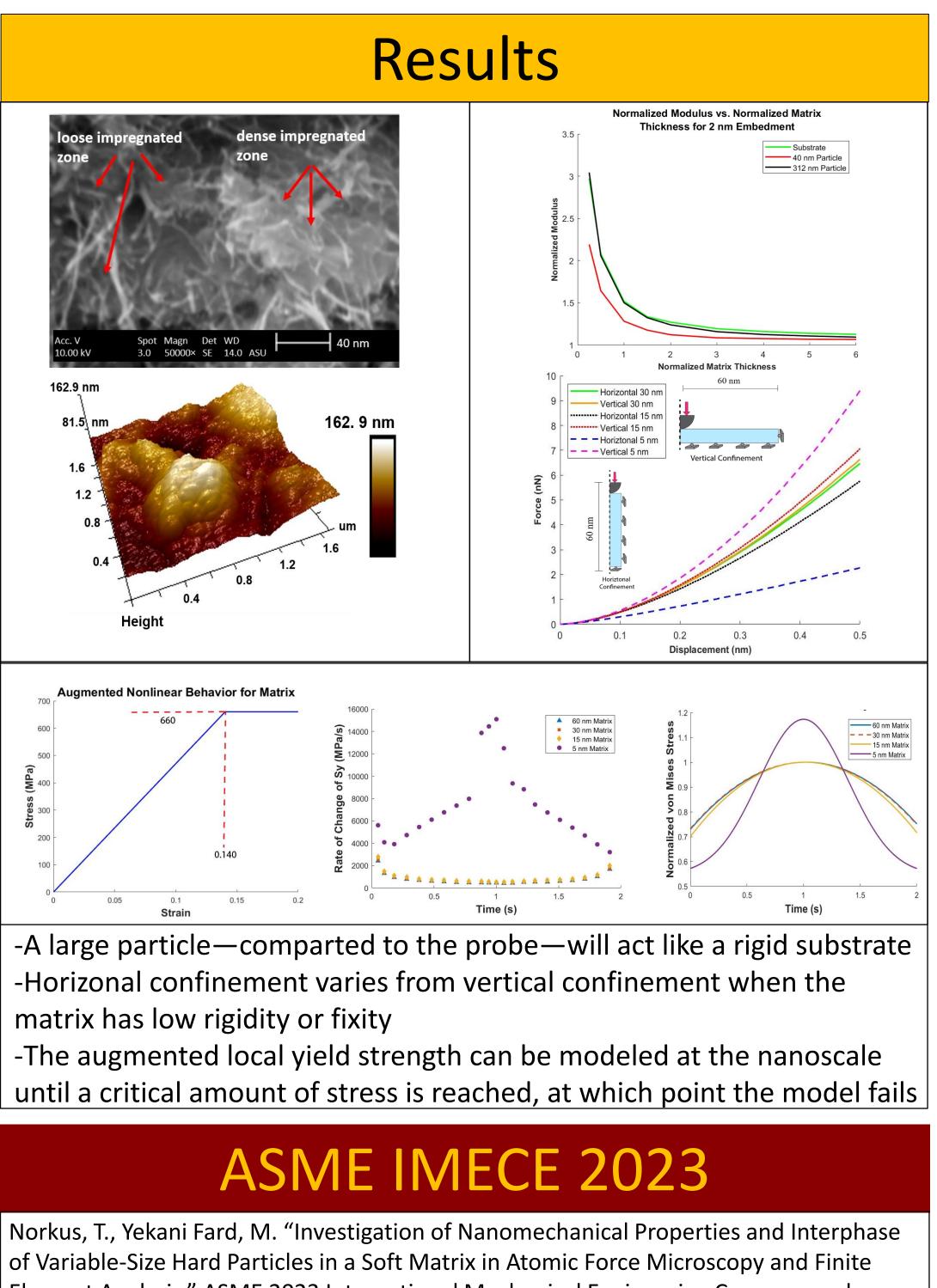
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Abstract

Inclusions and particles within nanoscale products affect their macro- and micro-scale properties, so those particles and the surrounding area must be characterized to improve product quality. Atomic force microscopy (AFM) is a powerful technique that has been used to characterize such materials; however, interactions between the AFM indenter and the particles result in complex force-displacement data. In this research, finite element analysis (FEA) is used to model AFM performed on particles within a membrane to better understand their material properties and deconvolute materials properties and structural effects in AFM data.









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